

## TEST REPORT EN 60269-4

## Low-voltage fuses

## Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices

**Report Number.** ....: 03601-A-23D0187-S

**Date of issue** .....: 2024-04-25

Total number of pages...... 29

Name of Testing Laboratory Suzhou Electrical Apparatus Science Research Institute Co.,

preparing the Report...... Ltd.(EETI)

Applicant's name...... Zhejiang Tengen Electric Co Ltd

Province, P.R.China

Test specification:

**Standard** EN 60269-4:2009, EN 60269-4:2009/AMD1:2012,

EN 60269-4:2009/AMD2:2016

Test procedure .....: CCA Scheme

Non-standard test method .....: N/A

TRF template used ...... IECEE OD-2020-F1:2022, Ed.1.5

Test Report Form No. ..... EN60269\_4D

Test Report Form(s) Originator ....: CQC

Master TRF...... Dated 2023-08-17

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Test item description:	Fuse f	for the protection of semiconductor equipment
Trade Mark:	TENGEN	
Manufacturer:	_	ng Tengen Electric Co .,Ltd.
		ndustrial Area, Liushi Town, Yueqing City, Zhejiang
MadaUT		nce, P.R.China
Model/Type reference:	TGRS3Z-5EP	
Ratings	See Page 6	
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Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):		
☐ Testing Laboratory:		Suzhou Electrical Apparatus Science Research Institute Co., Ltd.(EETI)
Testing location/ address:		No.7 Yonghe Street, Binhe Road, New District, Suzhou, China
Tested by (name, function, signature):		Fang Gang (Team leader)
Approved by (name, function, signature):		Chen Yuan(Supervisor)
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Testing procedure: CTF Stage 1:		
Testing location/ address:		
Tested by (name, function, signature):		
Approved by (name, function, signature):		
☐ Testing procedure: CTF Stage 2:		
Testing location/ address:		
Tested by (name + signature):		
Witnessed by (name, function, signature). :		
Approved by (name, function, signature):		
☐ Testing procedure: CTF Stage 3:		
☐ Testing procedure: CTF Stage 4:		
Testing location/ address:		
Tested by (name, function, signature):		
Witnessed by (name, function, signature). :		
Approved by (name, function, signature):		
Supervised by (name, function, signature) :		